New Mask and vendor for 3D detectors

R. Bates, G. Pellegrini et al. at Glasgow and CNM

Introduction 3D geometry

Mask design

Details of items on the mask

Fabrication at CNM

ICEMOS Tech

Bump bonding

Introduction

 CNM and Glasgow have designed a mask set for 1um passivation
3D detector fabrication 0.4un Oxide

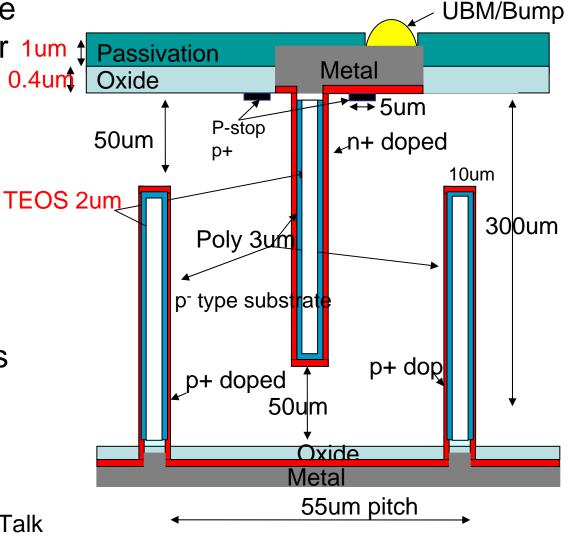
Mask ordered in past weeks

Funded by RD50
Common fund

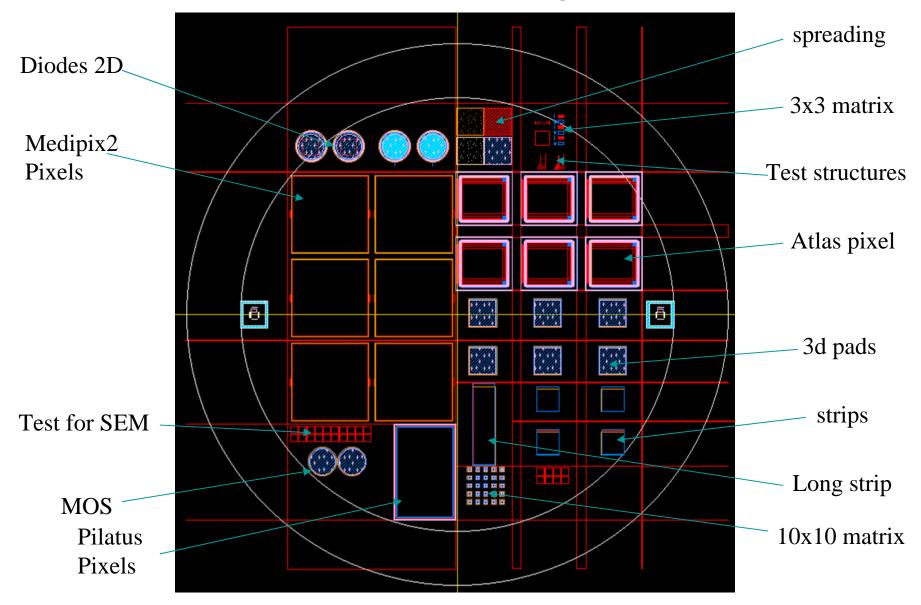
Request will arrive for 2kCHF from signatures

 Aim to fabricate devices at CNM with n- and ptype wafers

E-field and CCE simulated at Glasgow – Next Talk



Mask design



Device summary

- 6 Medipix2 pixels
- 6 ATLAS pixels
- 1 Pilatus pixel
- 4 short strip
- 1 long strip
- 6 pads
- 25 10x10 pads
- 25 3x3 pads
- 2 standard pads, diffusion
- 2 standard pads, poly
- 2 MOS structure
- Different test structure
- Structure for holes alignment

Pitch 55um, 256x256

Pitch 50x400um, 164x18

Pitch 172um, 97x60

Pitch 80um, 50x50

Pitch 80um, 180x50

Pitch 55um, 90x90

Pitch 55um, 10x10

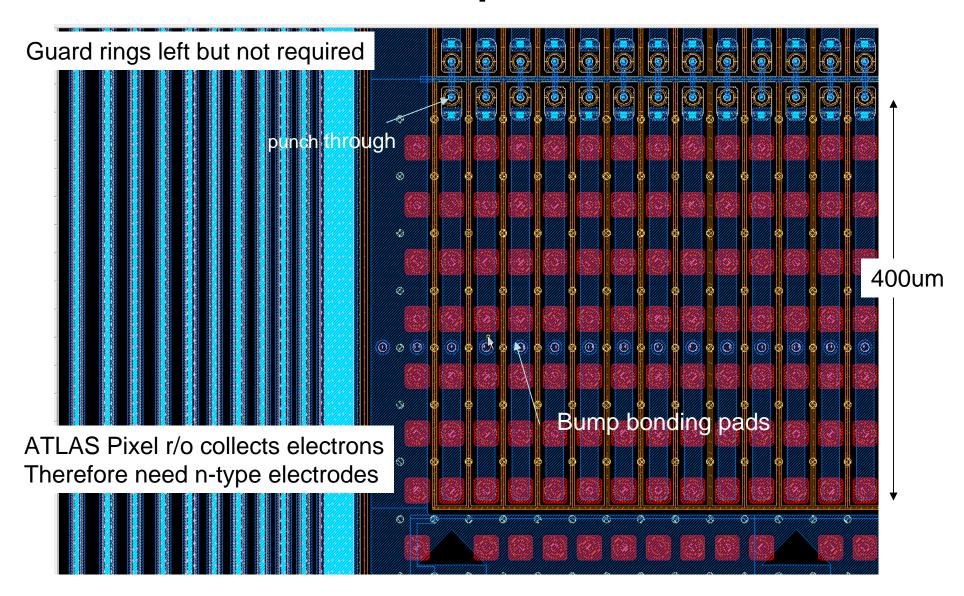
Pitch 55um, 3x3

Diameter: 5000um

Diameter: 5000um

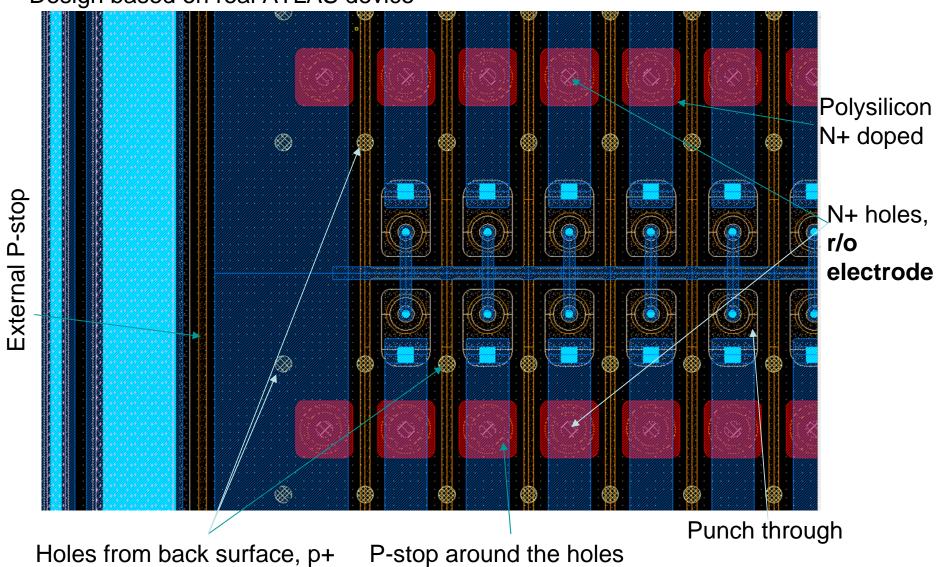
Diameter: 5000um

Atlas pixels

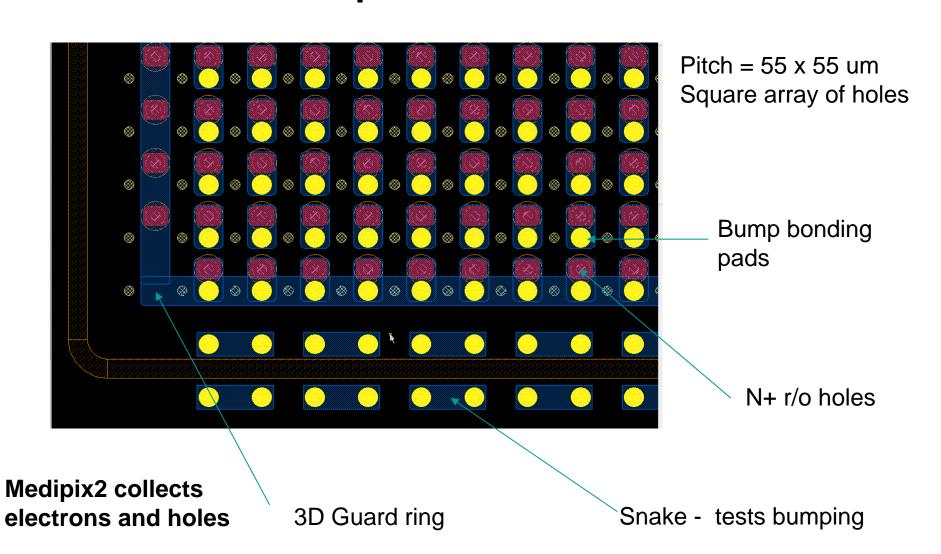


Atlas pixels

Design based on real ATLAS device



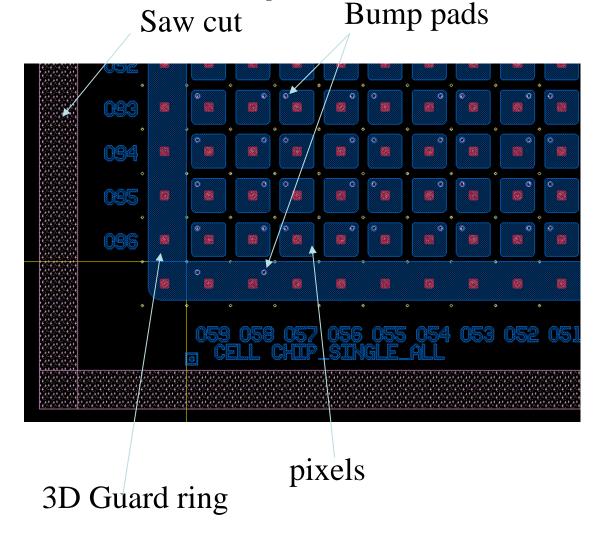
Medipix2 detector



Pilatus chip

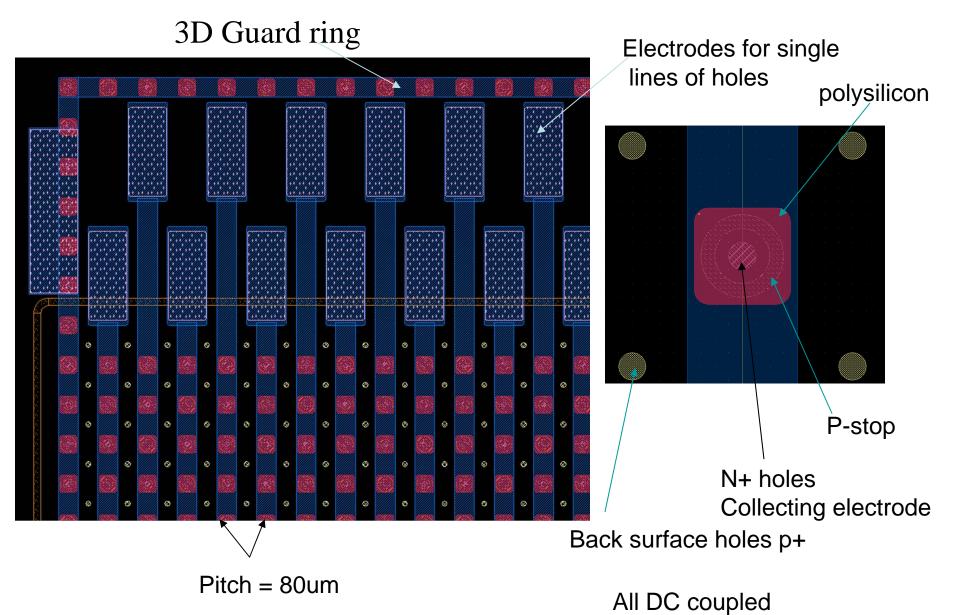
Pitch = $172 \times 172 \text{ um}$ Square array of holes

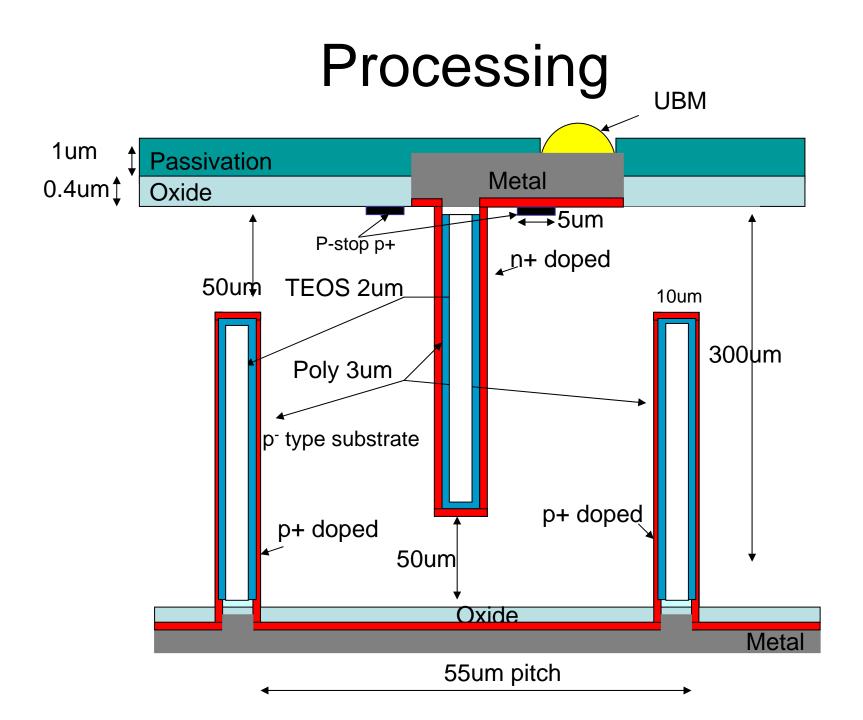
Pilatus r/o collects holes p-on-n type device required



PSI R/O for Synchrotron sources

Strip detectors





Process developed and checked Process flow:

Etch \Rightarrow Fill with Poly \Rightarrow P doping \Rightarrow TEOS \Rightarrow Etch \Rightarrow Poly \Rightarrow B doping \Rightarrow TEOS

Poly

- Hole etching working well
 - Aspect ratio 24:1
 - Better with Al mask
- 10um IMB-CNM-CSIC Date :5 Apr 2006 Mag = 11.54 K X Time:11:57:24 Aperture Size = 20.00 µm

- Doping down the hole works
 - Smooth profile at corners, not square
 - [B] same at top and bottom
- Study of P & B doping performed to obtain **TEOS** junction in crystal Si Junction down hole
 - Poly uniform down the hole
 - TEOS enters the hole

Processing plan

- 1st: p readout columns in an n-type bulk
- 2nd: n readout columns in a p-type bulk
- 9 wafers:
 - 1 wafer single sided for planar devices
 - 4 wafers with no bumps
 - 2 wafers for Medipix2 Sn/Ag bumps with Ni UBM left on strip pads
 - 2 with UBM for Indium Pilatus and ATLAS
 - Ratios may change due to bumping developments

IceMOS Technology Ltd

- Small N.I. Based silicon MEMS company
- Have all required equipment and skills for 3D
- 3 stage development plan negotiated
 - Dense high aspect ratio hole array development
 - Hole doping optimisation
 - Device fabrication
- We will supply new sets of masks
- Time scale to full devices order 6 months!

Bump bonding

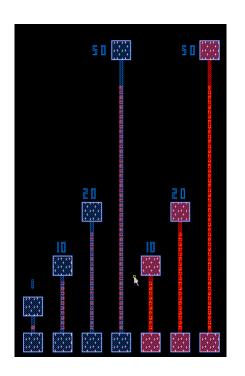
- Critical aspect for pixel devices
 - More effort required in this area with in RD50
- ATLAS r/o pixels in Glasgow with Indium bumps
- Pilatus Indium bumped at PSI
 - Diamond/RAL are building up a resource to work with PSI on bonding
- Medipix2 Solder bumps at CNM
- Freiburg to work on bumping 3D devices
- CNM produced Bump test device to check yield

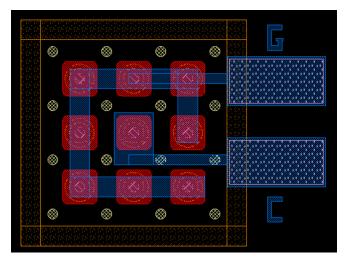
Summary

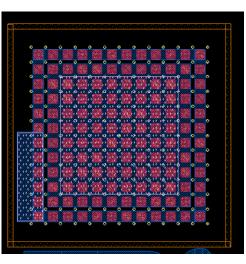
- Multi-project pixel 3D Mask designed
- Fabrication process understood
- 1st: p-in-n 3D detectors + single sided
- 2nd: n-in-p detectors
- End of 1st process foreseen for the end of October
 - if we get the mask before summer.
 - CNM clean room closed in August.
- Bump bonding unsolved issue
- Commercial 3D vendor being pursued

Extra Slides

Test structures







3x3 matrix

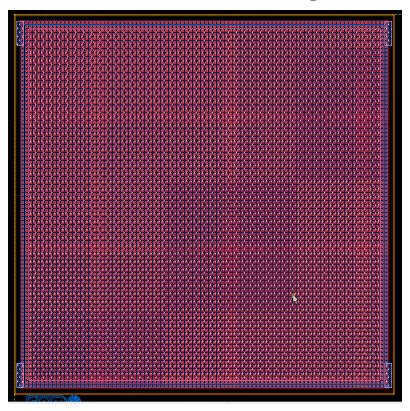
10x10 matrix

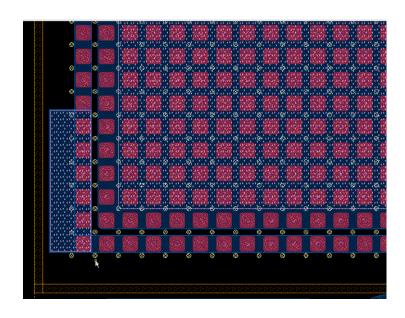
Test structure to measure the connection between the holes.

Standard Diode



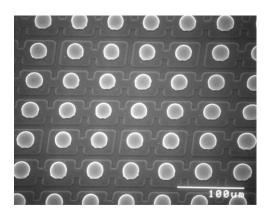
3D pad detectors

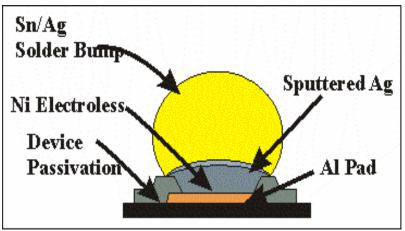




All holes connected by the metal layer

Bump bonding





- Minimum pitch: 40um
- Lead free technique
- Low cost process
- Fabrication steps:
- 1. Under Bump Metalisation (UBM)
- 2. Bump formation by electroplating
- 3. Reflow

